

### **DETAILED ACTION**

This office action is in response to the amendment filed May 15, 2008.

#### ***Response to Amendment***

The amendment of the specification is sufficient to overcome the objections to the specification stated in the previous office action. Therefore, these objections are withdrawn.

The limitations added to claims 1, 8, 10, 12, 14, 15, 16 and 17 are sufficient to overcome the Andriessen (US 6,929,970) reference. Therefore, the rejections of claims 1-17 under 35 U.S.C. 102(e) are hereby withdrawn.

#### ***Allowable Subject Matter***

Claims 1-18 are allowed.

The following is an examiner's statement of reasons for allowance:

The primary reasons for the allowance of claims 1-18 is in the inclusion therein, in combination as currently claimed, of the limitations of forming a semiconductor electrode by coating a paste including a binder and semiconductor nanoparticles on a substrate, drying the paste and afterwards using a pressing device to press the paste to bond the semiconductor nanoparticles onto the substrate while heating it. These limitations were found in claims 1-18 and are neither disclosed nor taught by the prior art of record, alone or in combination.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

### **EXAMINER'S AMENDMENT**

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The application has been amended as follows:

In the claims:

In line 8 of claim 1, delete "30C" and replace it with "30°C".

In line 2 of claim 2, delete "50C" and replace it with "50°C".

In line 2 of claim 3, delete "200C" and replace it with "200°C".

In line 2 of claim 4, delete "50C" and replace it with "50°C".

In line 2 of claim 4, delete "120C" and replace it with "120°C".

In line 8 of claim 8, delete "30C" and replace it with "30°C".

In line 8 of claim 10, delete "30C" and replace it with "30°C".

In line 8 of claim 12, delete "30C" and replace it with "30°C".

In line 7 of claim 14, delete "30C" and replace it with "30°C".

In line 8 of claim 15, delete "30C" and replace it with "30°C".

In line 7 of claim 16, delete "30C" and replace it with "30°C".

In line 8 of claim 17, delete "30C" and replace it with "30°C".

***Conclusion***

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Christy L. Novacek whose telephone number is (571) 272-1839. The examiner can normally be reached on Monday-Friday 4:00pm - 8:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Zandra Smith can be reached on (571) 272-2429. The fax phone number for the organization where this application or proceeding is assigned is (571) 273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

CLN  
June 8, 2008  
/Zandra V. Smith/  
Supervisory Patent Examiner, Art Unit 2822